

## **Phenom ProX Desktop SEM Imaging & X-ray Analysis System**

Viewing three dimensional images of microscopic areas only solves half the problem when analysing a sample and it is often necessary to identify the different elements associated with a specimen. The Phenom ProX solves this problem by providing an easy to use EDS elemental analysis system in a desktop package. EDS is an analytical technique which can analyze X-rays that are generated by the specimen when bombarded by the high quality Phenom CeB6 electron beam to identify the elemental composition of the specimen. SEM imaging of a sample from production can reveal contamination with an unknown substance or the inclusion of unknown particles.

The EDS system is fully integrated in the Phenom Pro system series as part of the Phenom Pro Suite application solution. The state of the art EDS-detector is completely embedded in the Phenom ProX and does not require any additional cabling or customer setup. This makes installation and operation of the system seamless and worry free. When operating the system, any feature can be imaged and analyzed without switching between PC's or systems.

The Phenom ProX EDS elemental analysis system is as easy to use as the microscope itself. Users have access to analysis with exactly the same ease of use they are used to with imaging mode. With the Phenom integrated X-ray analysis these particles can be examined and their composition and potential origin easily revealed. X-ray analysis is also important when monitoring a production process that needs to create a consistent material mix or specific consistence of materials, such as the fabrication of alloys and ceramics.